

ON Semiconductor

Is Now



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ON Semiconductor®

FDB070AN06A0-F085

N-Channel PowerTrench® MOSFET

60V, 80A, 7mΩ

Features

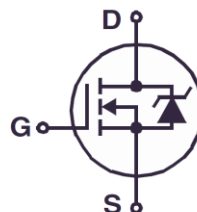
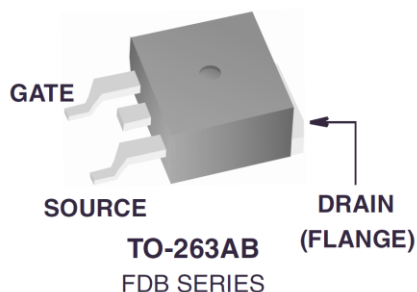
- $r_{DS(ON)} = 6.1\text{m}\Omega$ (Typ.), $V_{GS} = 10\text{V}$, $I_D = 80\text{A}$
- $Q_{g(tot)} = 51\text{nC}$ (Typ.), $V_{GS} = 10\text{V}$
- Low Miller Charge
- Low Q_{RR} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



Formerly developmental type 82567

Applications

- Motor / Body Load Control
- ABS Systems
- Powertrain Management
- Injection Systems
- DC-DC converters and Off-line UPS
- Distributed Power Architectures and VRMs
- Primary Switch for 12V and 24V systems



Ordering Information

Device	Output Voltage	Marking	Package	Shipping
FDB070AN06A0-F085	TBD	FDB070AN06A0	TO-263AB	Tape and Reel

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Ratings	Unit
V_{DS}	Drain to Source Voltage	60	V
V_{GS}	Gate to Source Voltage	± 20	V
I_D	Drain Current		
	Continuous ($T_C < 97^\circ\text{C}$, $V_{GS} = 10\text{V}$)	80	A
	Continuous ($T_A = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$, $R_{\theta JA} = 43^\circ\text{C/W}$)	15	A
	Pulsed	Figure 4	A
E_{AS}	Single Pulse Avalanche Energy ⁽¹⁾	190	mJ
P_D	Power dissipation	175	W
	Derate above 25°C	1.17	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-220, TO-263	0.86	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-220, TO-263 ⁽²⁾	62	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263, 1in ² copper pad area	43	$^\circ\text{C/W}$

Notes:

1. Starting $T_J = 25^\circ\text{C}$, $L = 93\ \mu\text{H}$, $I_{AS} = 64\text{A}$.
2. Pulse width = 100s.

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. All ON Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
Off Characteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	60			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 50 V V _{GS} = 0 V T _C = 150 °C			1 250	μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V			±100	nA
On Characteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250μA	2		4	V
r _{DS(ON)}	Drain to Source On Resistance	I _D = 80A, V _{GS} = 10V I _D = 80A, V _{GS} = 10V, T _J = 175°C		0.0061 0.0127	0.007 0.015	Ω
Dynamic Characteristics						
C _{ISS}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0 V, F = 1 MHz		3000		pF
C _{OSS}	Output Capacitance			510		pF
C _{RSS}	Reverse Transfer Capacitance			230		pF
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V	V _{DD} = 30 V I _D = 80 A I _g = 1.0 mA	51	66	nC
Q _{g(TH)}	Threshold Gate Charge	V _{GS} = 0V to 2V		5.4	7	nC
Q _{gs}	Gate to Source Gate Charge			17		nC
Q _{gs2}	Gate Charge Threshold to Plateau			11.6		nC
Q _{gd}	Gate to Drain “Miller” Charge			16		nC
Switching Characteristics (V _{GS} = 10 V)						
t _{ON}	Turn-On Time	V _{DD} = 30 V, I _D = 80 A V _{GS} = 10 V, R _{GS} = 5.6 Ω			256	ns
T _{d(ON)}	Turn-On Delay Time			12		ns
t _r	Rise Time			159		ns
T _{d(OFF)}	Turn-Off Delay Time			27		ns
t _f	Fall Time			35		ns
t _{OFF}	Turn-Off Time				93	ns
Drain-Source Diode Characteristics						
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 80 A			1.25	V
		I _{SD} = 40 A			1.0	V
t _{rr}	Reverse Recovery Time	I _{SD} = 75 A, dI _{SD} /dt = 100 A/μs			67	ns
Q _{RR}	Reverse Recovered Charge	I _{SD} = 75 A, dI _{SD} /dt = 100 A/μs			80	nC

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

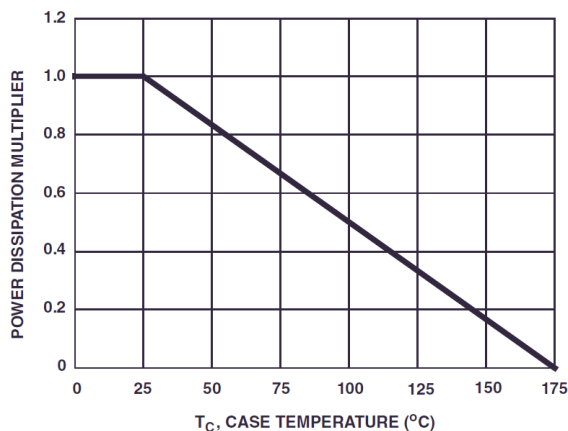


Figure 1. Normalized Power Dissipation vs Ambient Temperature

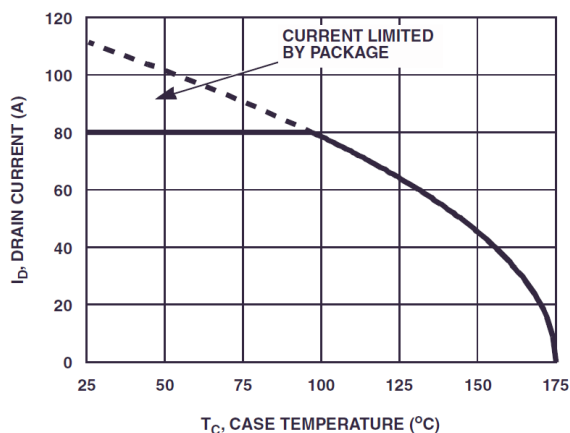


Figure 2. Maximum Continuous Drain Current vs Case Temperature

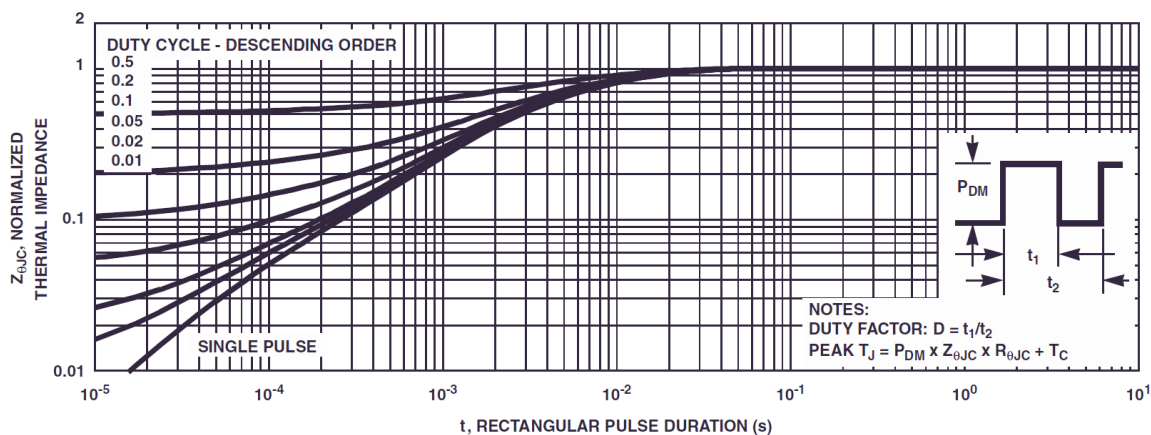


Figure 3. Normalized Maximum Transient Thermal Impedance

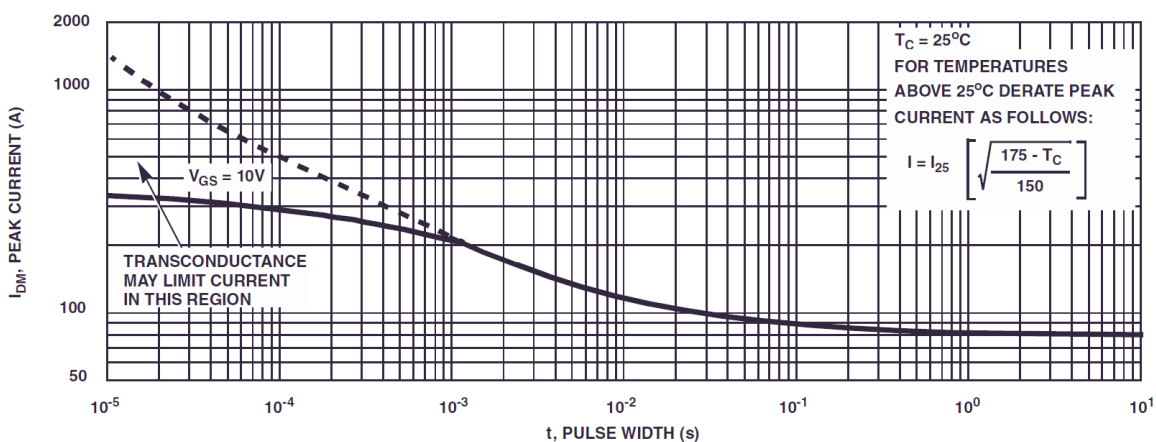


Figure 4. Peak Current Capability

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

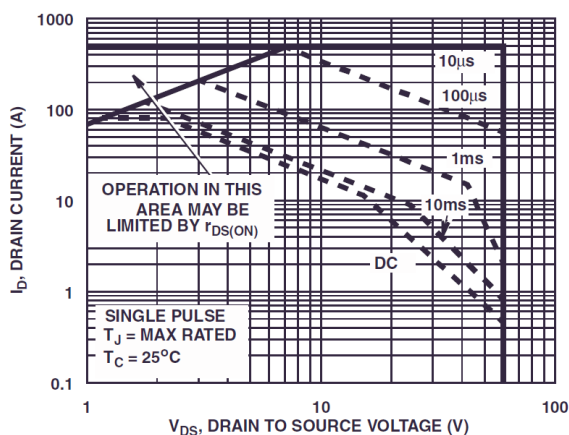
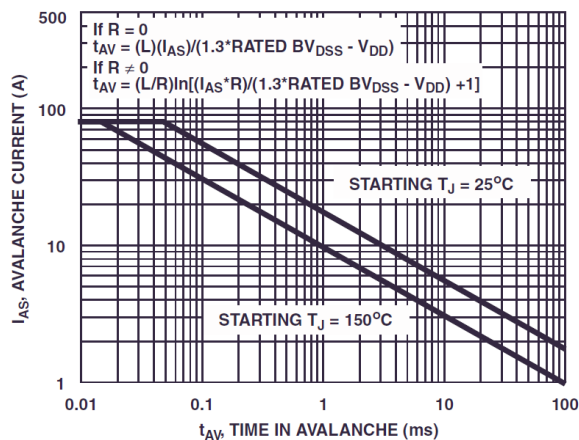


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to ON Semiconductor Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

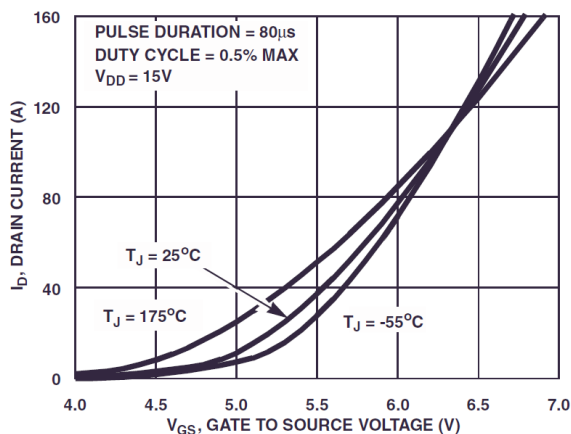


Figure 7. Transfer Characteristics

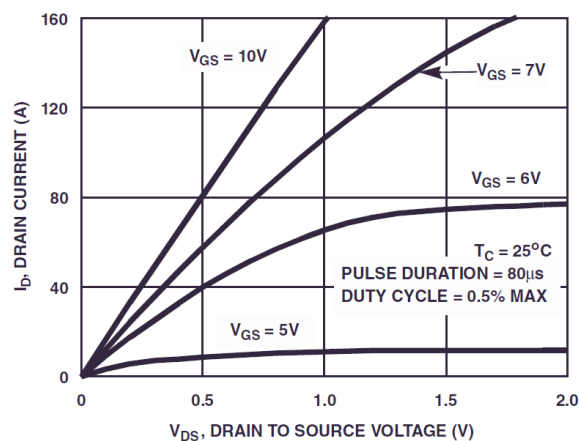


Figure 8. Saturation Characteristics

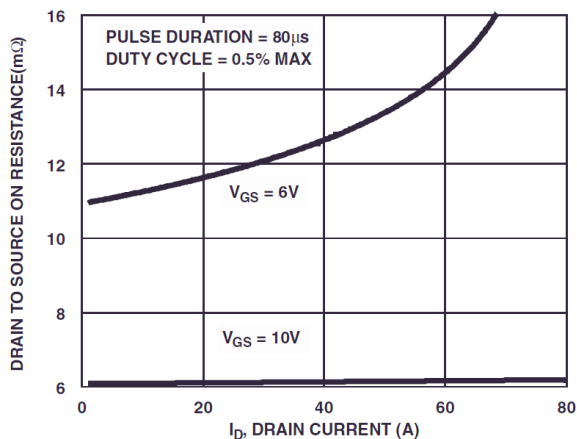


Figure 9. Drain to Source On Resistance vs Drain Current

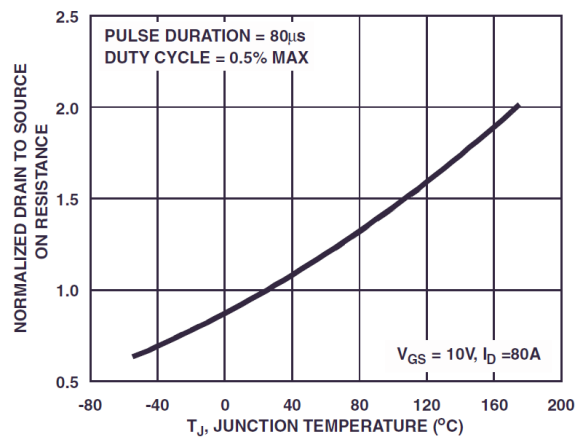


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

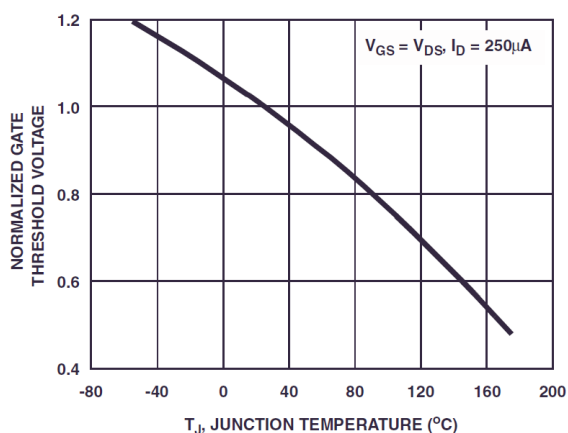


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

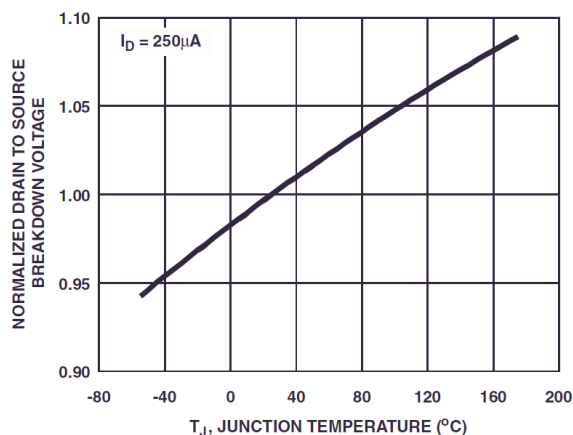


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

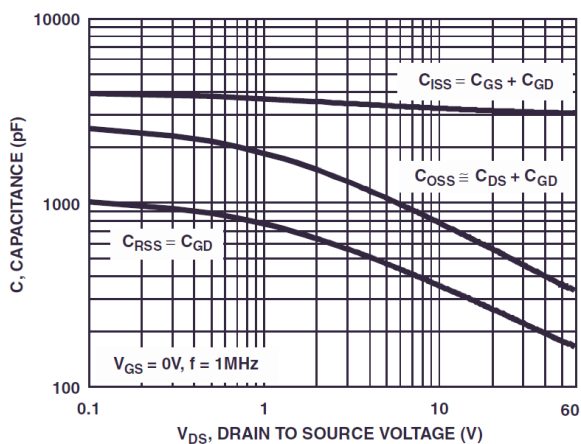


Figure 13. Capacitance vs Drain to Source Voltage

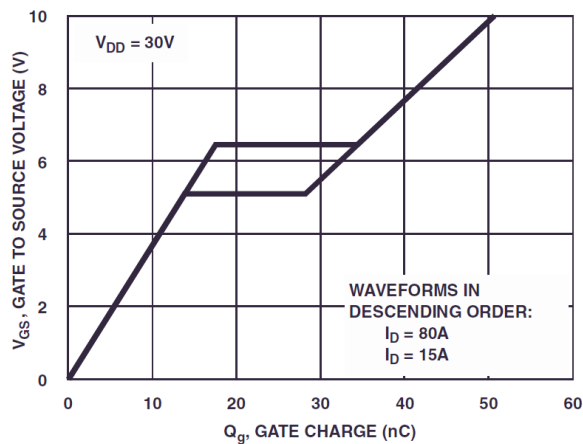


Figure 14. Gate Charge Waveforms for Constant Gate Current

Test Circuits and Waveforms

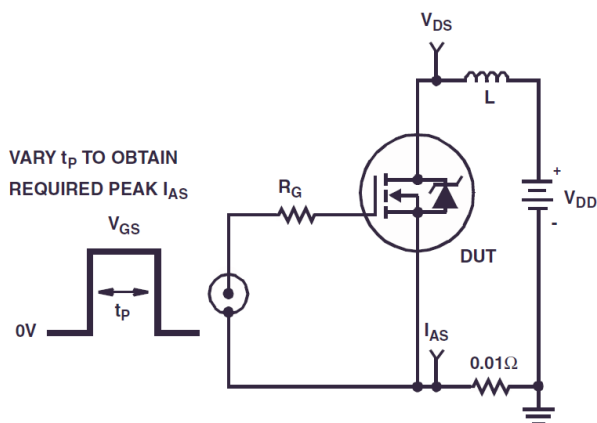


Figure 15. Unclamped Energy Test Circuit

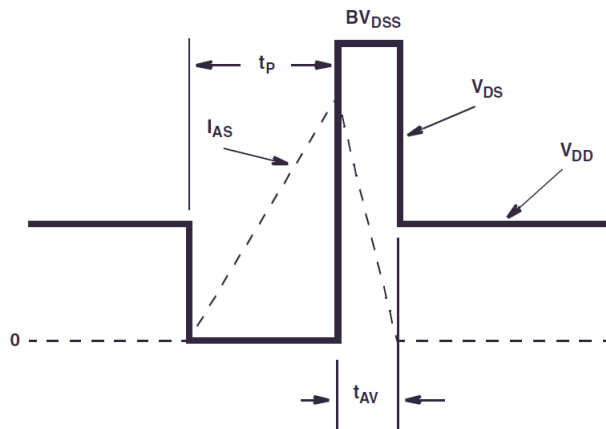


Figure 16. Unclamped Energy Waveforms

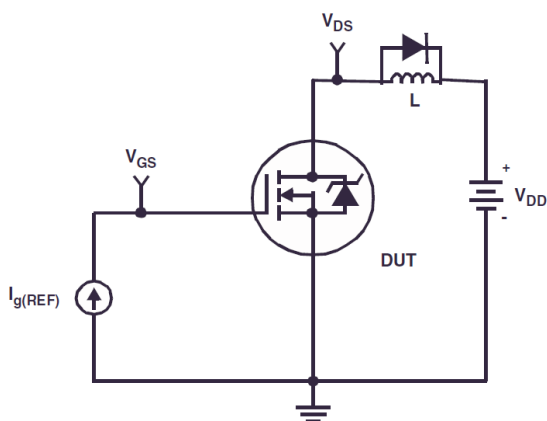


Figure 17. Gate Charge Test Circuit

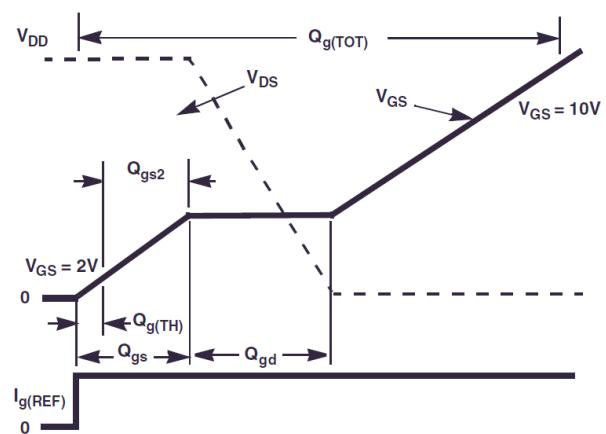


Figure 18. Gate Charge Waveforms

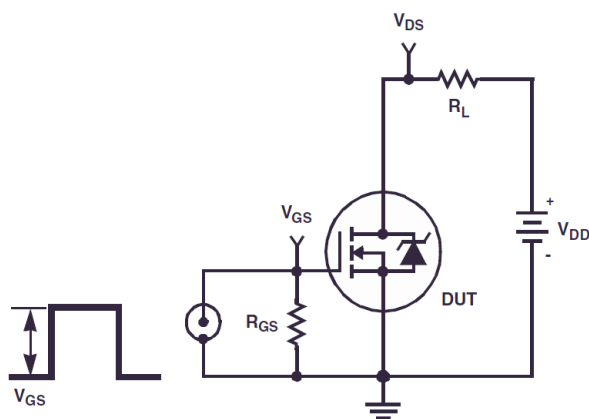


Figure 19. Switching Time Test Circuit

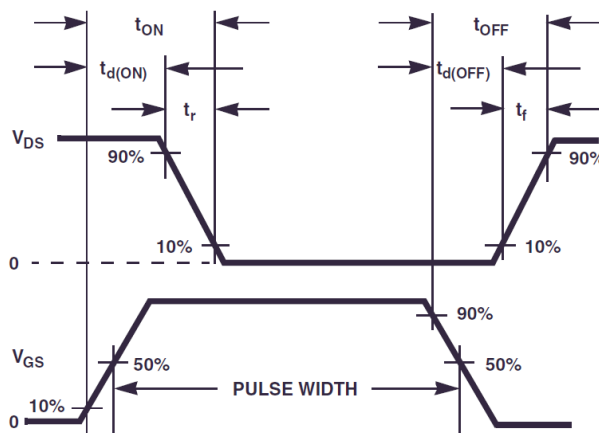


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \quad (\text{EQ. 1})$$

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

ON Semiconductor provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the ON Semiconductor device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + \text{Area})} \quad (\text{EQ. 2})$$

Area in Inches Squared

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + \text{Area})} \quad (\text{EQ. 3})$$

Area in Centimeters Squared

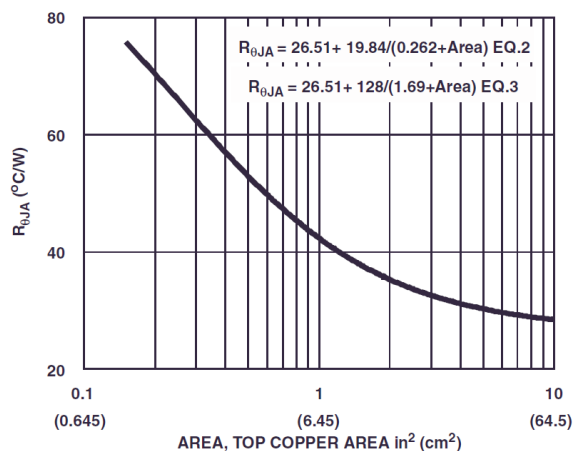


Figure 21. Thermal Resistance vs Mounting Pad Area

PSPICE Electrical Model

.SUBCKT FDB070AN06A0 2 1 3 ; rev March 2003
 Ca 12 8 1.5e-9
 Cb 15 14 1.5e-9
 Cin 6 8 2.9e-9

Dbody 7 5 DbodyMOD
 Dbreak 5 11 DbreakMOD
 Dplcap 10 5 DplcapMOD

Ebreak 11 7 17 18 62
 Eds 14 8 5 8 1
 Egs 13 8 6 8 1
 Esg 6 10 6 8 1
 Evthres 6 21 19 8 1
 Evtemp 20 6 18 22 1

It 8 17 1

Lgate 1 9 4.8e-9
 Ldrain 2 5 1.0e-9
 Lsource 3 7 3e-9

RLgate 1 9 48
 RLdrain 2 5 10
 RLsource 3 7 3

Mmed 16 6 8 8 MmedMOD
 Mstro 16 6 8 8 MstroMOD
 Mweak 16 21 8 8 MweakMOD

Rbreak 17 18 RbreakMOD 1
 Rdrain 50 16 RdrainMOD 1.3e-3
 Rgate 9 20 2.7
 RSLC1 5 51 RSLCMOD 1e-6
 RSLC2 5 50 1e3
 Rsource 8 7 RsourceMOD 3.1e-3
 Rvthres 22 8 RvthresMOD 1
 Rvtemp 18 19 RvtempMOD 1
 S1a 6 12 13 8 S1AMOD
 S1b 13 12 13 8 S1BMOD
 S2a 6 15 14 13 S2AMOD
 S2b 13 15 14 13 S2BMOD

Vbat 22 19 DC 1
 ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*250),10))}

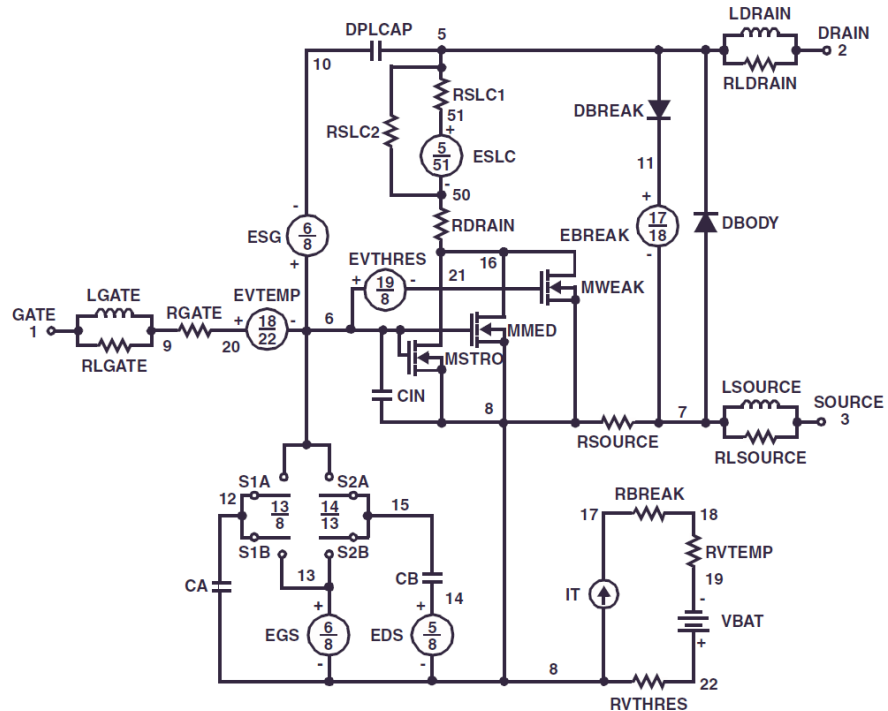
.MODEL DbodyMOD D (IS=7.6E-12 N=1.04 RS=2.2e-3 TRS1=2.7e-3 TRS2=2e-7
 + CJO=1.6e-9 M=0.55 TT=5e-12 XTI=3.9)
 .MODEL DbreakMOD D (RS=8e-1 TRS1=5e-4 TRS2=-8.9e-6)
 .MODEL DplcapMOD D (CJO=1.05e-9 IS=1e-30 N=10 M=0.45)

.MODEL MmedMOD NMOS (VTO=3.7 KP=10 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.7)
 .MODEL MstroMOD NMOS (VTO=4.7 KP=100 IS=1e-30 N=10 TOX=1 L=1u W=1u)
 .MODEL MweakMOD NMOS (VTO=3.01 KP=0.03 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=27 RS=0.1)

.MODEL RbreakMOD RES (TC1=7.1e-4 TC2=-5.5e-7)
 .MODEL RdrainMOD RES (TC1=1.7e-2 TC2=4e-5)
 .MODEL RSLCMOD RES (TC1=3e-3 TC2=1e-5)
 .MODEL RsourceMOD RES (TC1=1e-3 TC2=1e-6)
 .MODEL RvthresMOD RES (TC1=-5.2e-3 TC2=-1.5e-5)
 .MODEL RvtempMOD RES (TC1=-3e-3 TC2=1.3e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-2)
 .MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-4)
 .MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.5 VOFF=0.5)
 .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=0.5 VOFF=-1.5)
 .ENDS

Note: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.



PSPICE Thermal Model

REV 23 March 2003

FDB070AN06A0T

CTHERM1 TH 6 3.5e-3
 CTHERM2 6 5 1.7e-2
 CTHERM3 5 4 1.8e-2
 CTHERM4 4 3 1.9e-2
 CTHERM5 3 2 4.7e-2
 CTHERM6 2 TL 7e-2

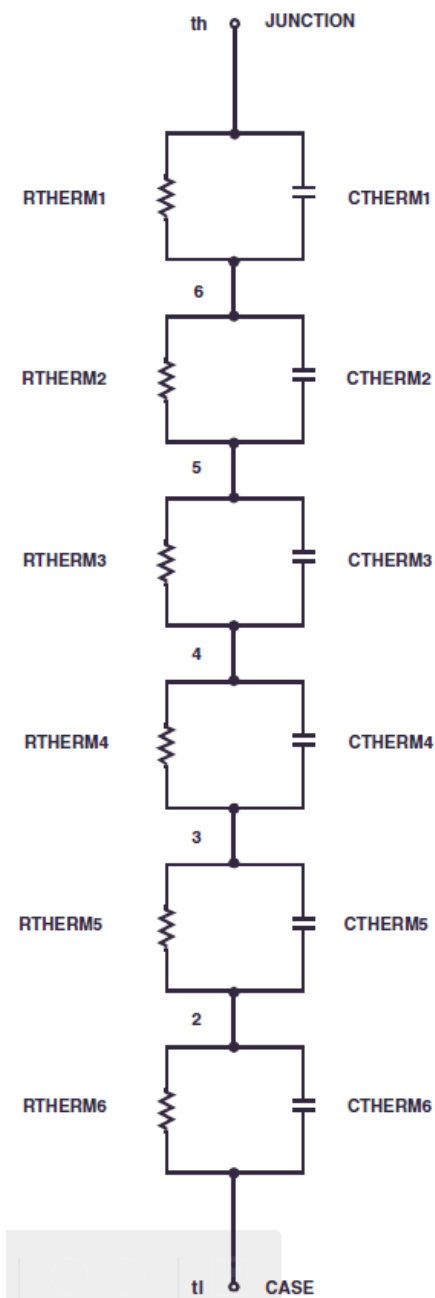
RTHERM1 TH 6 2e-2
 RTHERM2 6 5 7e-2
 RTHERM3 5 4 1e-1
 RTHERM4 4 3 1.5e-1
 RTHERM5 3 2 1.6e-1
 RTHERM6 2 TL 1.85e-1

SABER Thermal Model

SABER thermal model FDB070AN06A0T
 template thermal_model th tl
 thermal_c th, tl

```
{
  ctherm.ctherm1 th 6 =3.5e-3
  ctherm.ctherm2 6 5 =1.7e-2
  ctherm.ctherm3 5 4 =1.8e-2
  ctherm.ctherm4 4 3 =1.9e-2
  ctherm.ctherm5 3 2 =4.7e-2
  ctherm.ctherm6 2 tl =7e-2
```

```
  rtherm.rtherm1 th 6 =2e-2
  rtherm.rtherm2 6 5 =7e-2
  rtherm.rtherm3 5 4 =1e-1
  rtherm.rtherm4 4 3 =1.5e-1
  rtherm.rtherm5 3 2 =1.6e-1
  rtherm.rtherm6 2 tl =1.85e-1
}
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Physical Dimensions

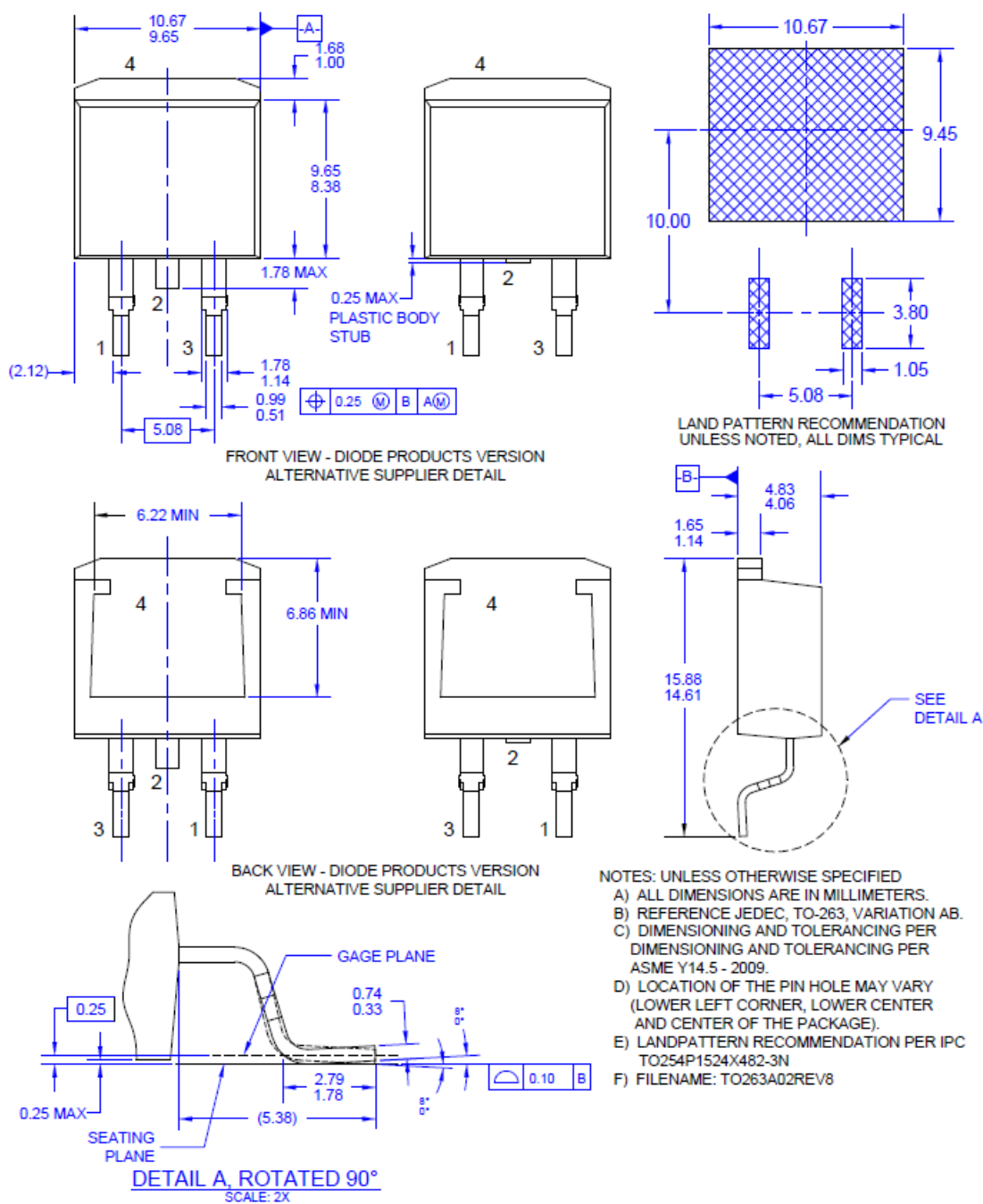


Figure 22. TO-263 2L (D2PAK), 4.445 x 10.16 x 15.24mm, TAPE REEL

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